



FIRST INTERNATIONAL NANOTECHNOLOGY CONFERENCE ON COMMUNICATION AND COOPERATION

Abstract

Introduction of Nano-scale-application Tools

Anto Yasaka

Recently, various types of nano-scale-application tools are newly developed and they spread widely. SII NanoTechnology has also been developing a new SPM (Scanning Probe Microscope) system and a new FIB (Focused Ion Beam) system. They are capable of observation, evaluation, fabrication and manipulation of the nano-scale materials and structure. We will introduce several examples of nano-scale applications with our newly developed tools, including experimental proof of existing mass in magnetic wall movement using the SPM technology.